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RCE/2877
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani et al.
Title: Improved Sample Inspection System
I.A. Application No.: PCT/US98/19564 I.A. Filing Date: 09/18/1998
Application No.: 10/070,079 Priority Date: 09/19/1997
Examiner: Hoa Q. Pham Group Art Unit: 2877
Docket No.: TNCR.152US5 Conf. No.: 7208

Mail Stop Petitions
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REQUEST FOR CONTINUED EXAMINATION (RCE)

Dear Sir:

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application.

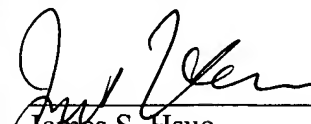
Please consider the Information Disclosure Statement which is being filed herewith. The RCE fee required under 37 C.F.R. § 1.17(e) is authorized in an accompanying transmittal letter.

Please contact the undersigned attorney with any questions concerning this request or the above-identified patent application.

EXPRESS MAIL NO.:

EV437667819US

Respectfully submitted,


James S. Hsue
Reg. No. 29,545

8/23/04
Date